

Supporting Information

Sign Reversal of Magneto-Capacitance in an Organic Heterojunction based Opto-Spintronic System

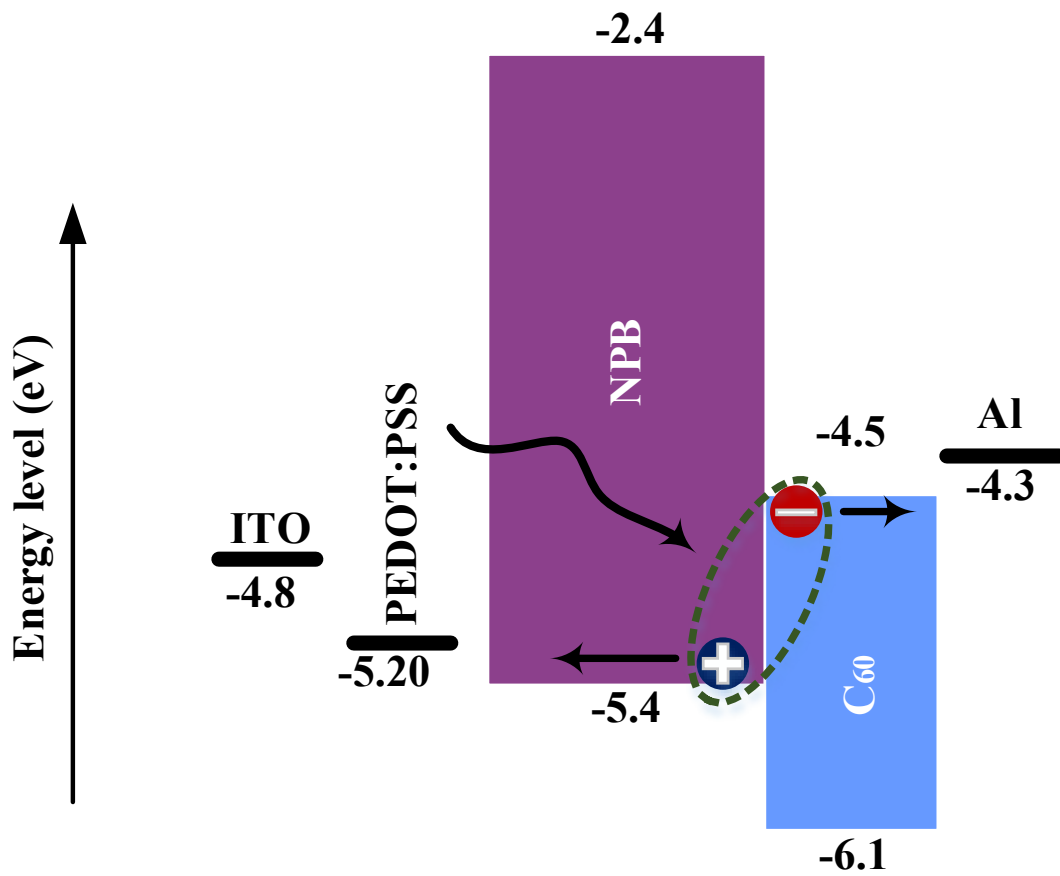
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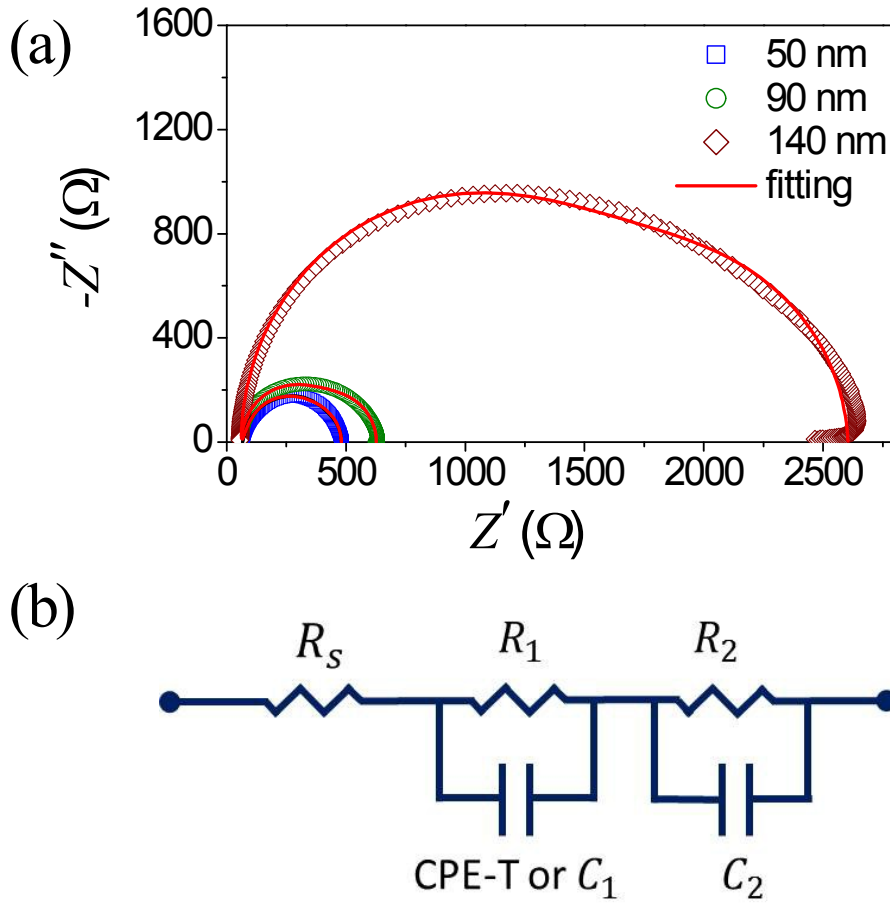
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S-Fig. 1 The schematic picture illustrates the energy alignment of the materials for the device configuration (ITO(glass)/PEDOT:PSS(30 nm)/NPB(50 nm, 90 nm, 140 nm)/C₆₀(30 nm)/Al(100 nm)). The electron-hole pair was created under photo-excitation and further diffuse to the two separated electrodes.



S-Fig. 2 (a) The cole-cole (Nyquist) plots of the devices (ITO(glass)/PEDOT:PSS(30 nm)/NPB(50 nm, 90 nm, 140 nm)/C₆₀(30 nm)/Al(100 nm)) measured under 1000 mW/cm² illumination with the absence of the magnetic field, the red lines are the fitting curves. (b) The equivalent electronic circuit for the devices. R_s represents the series resistance. R_1 and C_1 are the corresponding resistance and capacitance measured at lower *ac*-modulation frequencies due to the NPB surface resistance and capacitance. As we can see from S-Table 1, the decrease of the NPB layer thickness from 140 nm to 50 nm leads to the reduction of C_1 . R_2 and C_2 are the corresponding resistance and capacitance measured at higher frequencies due to the bulk resistance/geometric capacitance (C_{geo}). Apparently, as it is indicated in S-Table 1, the increase of the NPB layer thickness leads to the decrease of C_2 because $C_2 = C_{geo} = \epsilon_r \epsilon_0 \frac{A}{d}$. CPE stands for constant phase element, and it contains two parts CPE-T and CPE-P. Conventionally, the semi-circle of the impedance spectrum can be modeled by a simple *RC* component. However, the lower frequency part may require a constant phase element (*CPE*) under a certain circumstance

and it contains two major parts, a pseudo-capacitance (*CPE-T*) represented by Q , and a semi-circle depression element (*CPE-P*) denoted by n . The *CPE* can thus be written as

$CPE = R \left(\frac{1-n}{n}\right) \cdot Q \left(\frac{1}{n}\right)$, in which R represents resistance. If n approaches 1, the *CPE* turns theoretically to a capacitor.

S-Tab. 1 The fitting parameters for the equivalent circuit of S-Figure 2(b).

NPB Thickness	R_s	R_1	CPE-T or C_1	CPE-P	R_2	C_2
140 nm	60.26	1005	2.03×10^{-8}	0.968	1509	1.78×10^{-9}
90 nm	60.85	224	1.88×10^{-8}	-	342.3	2.49×10^{-9}
50 nm	65.40	15.4	8.10×10^{-9}	-	399	4.50×10^{-9}